### Sixty-sixth Annual Meeting Papers

Techniques of

# ELECTRON MICROSCOPY, DIFFRACTION, and MICROPROBE ANALYSIS



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### TECHNIQUES OF ELECTRON MICROSCOPY, DIFFRACTION, AND MICROPROBE ANALYSIS

## Presented at the Sixty-sixth Annual Meeting AMERICAN SOCIETY FOR TESTING AND MATERIALS Atlantic City, N. J., June 26, 1963



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#### FOREWORD

The papers in this volume were presented at a Symposium on Electron Metallography, sponsored by Subcommittee XI on Electron Microstructure of Metals of ASTM Committee E-4 on Metallography, which was held on June 26, 1963, during the Sixty-sixth Annual Meeting of the Society.

The conference chairman was J. R. Mihalisin, of the International Nickel Co. W. R. Lasko, of Pratt and Whitney Aircraft Division of United Aircraft Corp., presided over the technical sessions.

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### CONTENTS

	PAGE
Introduction	1
Specimen Damage During Cutting and Grinding—A. Szirmae and R. M. Fisher	3
Electron Microscopy of Stress-Corrosion Cracking in AM 350 Steel for Supersonic	
Transport—N. A. Tiner	10
Application of a Conducting Mask for Thinning Metallic Foils for Electron Trans-	
mission Microscopy—Thomas A. Despres	24
Investigation of Microstructure and Room-Temperature Fracture in SM-200 Nickel-	
Base Alloy—R. W. Hertzberg and J. A. Ford	31
Microconstituents in High-Speed Steel-P. K. Koh and H. Nikkel	44
Variable Bias Illumination Control for the Electron Microscope—J. O. McPartland	
and J. L. Daniel	51
Two New Indexes to the Powder Diffraction File—W. C. Bigelow and J. V. Smith	54

#### RELATED ASTM PUBLICATIONS

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THIS PUBLICATION is one of many issued by the American Society for Testing and Materials in connection with its work of promoting knowledge of the properties of materials and developing standard specifications and tests for materials. Much of the data result from the voluntary contributions of many of the country's leading technical authorities from industry, scientific agencies, and government.

Over the years the Society has published many technical symposiums, reports, and special books. These may consist of a series of technical papers, reports by the ASTM technical committees, or compilations of data developed in special Society groups with many organizations cooperating. A list of ASTM publications and information on the work of the Society will be furnished on request.

